

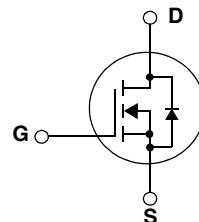
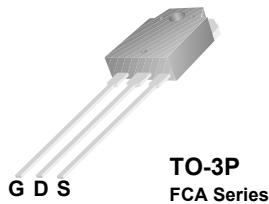
## FCA16N60 600V N-Channel MOSFET

### Features

- 650V @ $T_J = 150^\circ\text{C}$
- Typ.  $R_{ds(on)}=0.22\Omega$
- Ultra low gate charge (typ.  $Q_g=55\text{nC}$ )
- Low effective output capacitance (typ.  $C_{oss,eff}=110\text{pF}$ )
- 100% avalanche tested

### Description

SuperFET™ is, Fairchild's proprietary, new generation of high voltage MOSFET family that is utilizing an advanced charge balance mechanism for outstanding low on-resistance and lower gate charge performance. This advanced technology has been tailored to minimize conduction loss, provide superior switching performance, and withstand extreme dv/dt rate and higher avalanche energy. Consequently, SuperFET is very suitable for various AC/DC power conversion in switching mode operation for system miniaturization and higher efficiency.



### Absolute Maximum Ratings

Symbol	Parameter	FCA16N60	Unit
$V_{DSS}$	Drain-Source Voltage	600	V
$I_D$	Drain Current - Continuous ( $T_C = 25^\circ\text{C}$ ) - Continuous ( $T_C = 100^\circ\text{C}$ )	16 10.1	A A
$I_{DM}$	Drain Current - Pulsed	(Note 1)	48
$V_{GSS}$	Gate-Source voltage	$\pm 30$	V
$E_{AS}$	Single Pulsed Avalanche Energy	(Note 2)	450
$I_{AR}$	Avalanche Current	(Note 1)	16
$E_{AR}$	Repetitive Avalanche Energy	(Note 1)	16.7
$dv/dt$	Peak Diode Recovery $dv/dt$	(Note 3)	V/ns
$P_D$	Power Dissipation ( $T_C = 25^\circ\text{C}$ ) - Derate above $25^\circ\text{C}$	167 1.33	W W/ $^\circ\text{C}$
$T_J, T_{STG}$	Operating and Storage Temperature Range	-55 to +150	$^\circ\text{C}$
$T_L$	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds	300	$^\circ\text{C}$

\*Drain current limited by maximum junction temperature

### Thermal Characteristics

Symbol	Parameter	FCA16N60	Unit
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	0.75	$^\circ\text{C/W}$
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	41.7	$^\circ\text{C/W}$

## Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FCA16N60	FCA16N60	TO-3P	-	-	30
FCA16N60	FCA16N60_F109	TO-3PN	-	-	30

## Electrical Characteristics

$T_C = 25^\circ\text{C}$  unless otherwise noted

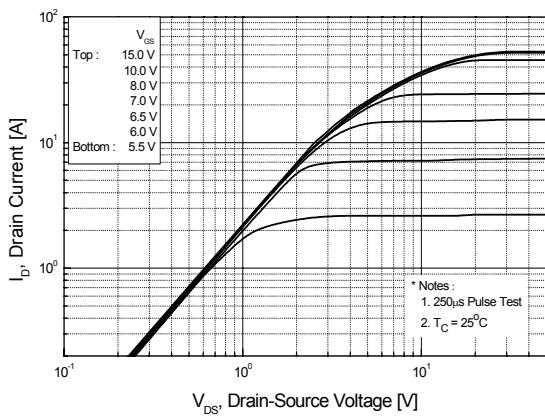
Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>Off Characteristics</b>						
$BV_{DSS}$	Drain-Source Breakdown Voltage	$V_{GS} = 0\text{V}, I_D = 250\mu\text{A}, T_J = 25^\circ\text{C}$	600	--	--	V
		$V_{GS} = 0\text{V}, I_D = 250\mu\text{A}, T_J = 150^\circ\text{C}$	--	650	--	V
$\Delta BV_{DSS} / \Delta T_J$	Breakdown Voltage Temperature Coefficient	$I_D = 250\mu\text{A}$ , Referenced to $25^\circ\text{C}$	--	0.6	--	$^\circ\text{C}$
$BV_{DS}$	Drain-Source Avalanche Breakdown Voltage	$V_{GS} = 0\text{V}, I_D = 16\text{A}$	--	700	--	V
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS} = 600\text{V}, V_{GS} = 0\text{V}$ $V_{DS} = 480\text{V}, T_C = 125^\circ\text{C}$	-- --	-- 10	1 10	$\mu\text{A}$
$I_{GSSF}$	Gate-Body Leakage Current, Forward	$V_{GS} = 30\text{V}, V_{DS} = 0\text{V}$	--	--	100	nA
$I_{GSSR}$	Gate-Body Leakage Current, Reverse	$V_{GS} = -30\text{V}, V_{DS} = 0\text{V}$	--	--	-100	nA
<b>On Characteristics</b>						
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	3.0	--	5.0	V
$R_{DS(\text{on})}$	Static Drain-Source On-Resistance	$V_{GS} = 10\text{V}, I_D = 8\text{A}$	--	0.22	0.26	$\Omega$
$g_{FS}$	Forward Transconductance	$V_{DS} = 40\text{V}, I_D = 8\text{A}$	(Note 4)	--	11.5	--
<b>Dynamic Characteristics</b>						
$C_{iss}$	Input Capacitance	$V_{DS} = 25\text{V}, V_{GS} = 0\text{V}, f = 1.0\text{MHz}$	--	1730	2250	pF
$C_{oss}$	Output Capacitance		--	960	1150	pF
$C_{rss}$	Reverse Transfer Capacitance		--	85	--	pF
$C_{oss}$	Output Capacitance	$V_{DS} = 480\text{V}, V_{GS} = 0\text{V}, f = 1.0\text{MHz}$	--	45	60	pF
$C_{oss \text{ eff.}}$	Effective Output Capacitance	$V_{DS} = 0\text{V to } 400\text{V}, V_{GS} = 0\text{V}$	--	110	--	pF
<b>Switching Characteristics</b>						
$t_{d(on)}$	Turn-On Delay Time	$V_{DD} = 300\text{V}, I_D = 16\text{A}$ $R_G = 25\Omega$	--	42	85	ns
$t_r$	Turn-On Rise Time		--	130	270	ns
$t_{d(off)}$	Turn-Off Delay Time		--	165	340	ns
$t_f$	Turn-Off Fall Time		--	90	190	ns
$Q_g$	Total Gate Charge	$V_{DS} = 480\text{V}, I_D = 16\text{A}$ $V_{GS} = 10\text{V}$	--	55	70	nC
$Q_{gs}$	Gate-Source Charge		--	10.5	13	nC
$Q_{gd}$	Gate-Drain Charge		(Note 4, 5)	--	28	--
<b>Drain-Source Diode Characteristics and Maximum Ratings</b>						
$I_S$	Maximum Continuous Drain-Source Diode Forward Current	--	--	16	A	
$I_{SM}$	Maximum Pulsed Drain-Source Diode Forward Current	--	--	48	A	
$V_{SD}$	Drain-Source Diode Forward Voltage	$V_{GS} = 0\text{V}, I_S = 16\text{A}$	--	--	1.4	V
$t_{rr}$	Reverse Recovery Time	$V_{GS} = 0\text{V}, I_S = 16\text{A}$ $dI_F/dt = 100\text{A}/\mu\text{s}$	--	435	--	ns
$Q_{rr}$	Reverse Recovery Charge		(Note 4)	--	7.0	--

### NOTES:

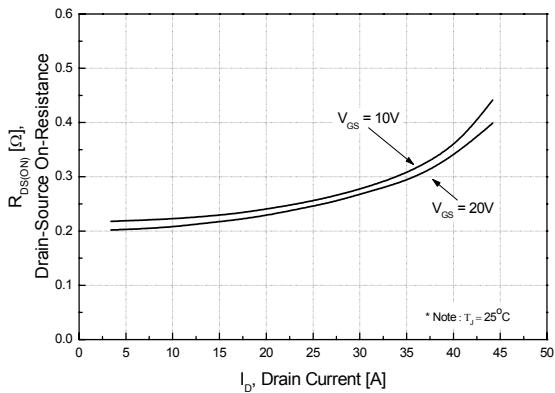
1. Repetitive Rating: Pulse width limited by maximum junction temperature
2.  $I_{AS} = 8\text{A}, V_{DD} = 50\text{V}, R_G = 25\Omega$ , Starting  $T_J = 25^\circ\text{C}$
3.  $I_{SD} \leq 16\text{A}, dI/dt \leq 200\text{A}/\mu\text{s}, V_{DD} \leq BV_{DSS}$ , Starting  $T_J = 25^\circ\text{C}$
4. Pulse Test: Pulse width  $\leq 300\mu\text{s}$ , Duty Cycle  $\leq 2\%$
5. Essentially Independent of Operating Temperature Typical Characteristics

## Typical Performance Characteristics

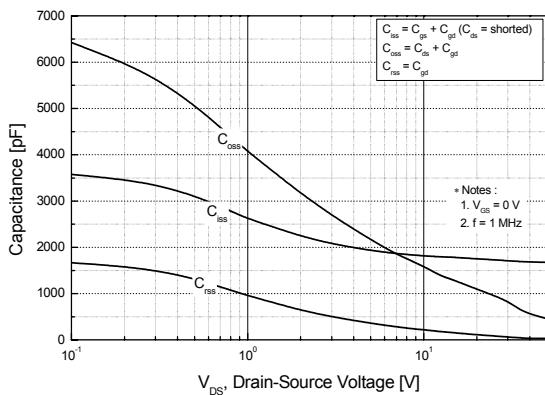
**Figure 1. On-Region Characteristics**



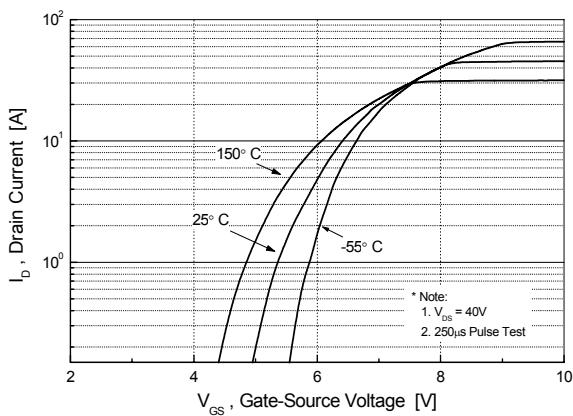
**Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage**



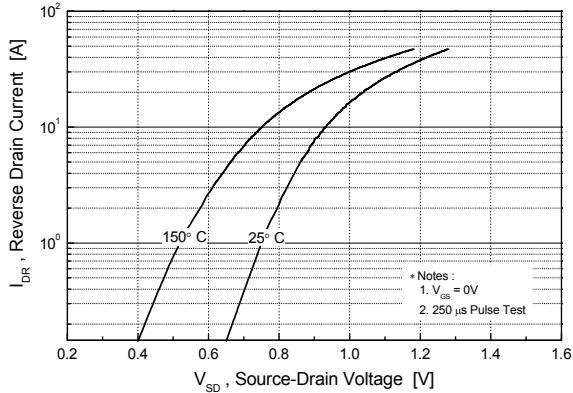
**Figure 5. Capacitance Characteristics**



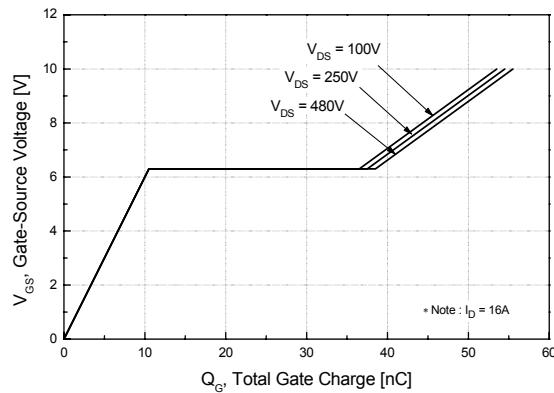
**Figure 2. Transfer Characteristics**



**Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature**

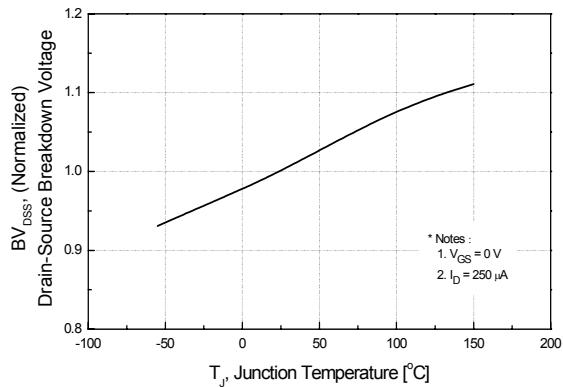


**Figure 6. Gate Charge Characteristics**

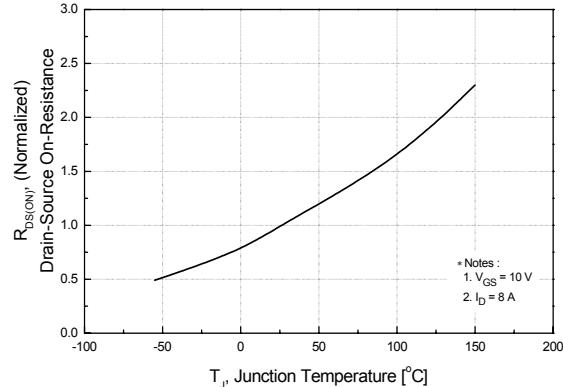


## Typical Performance Characteristics (Continued)

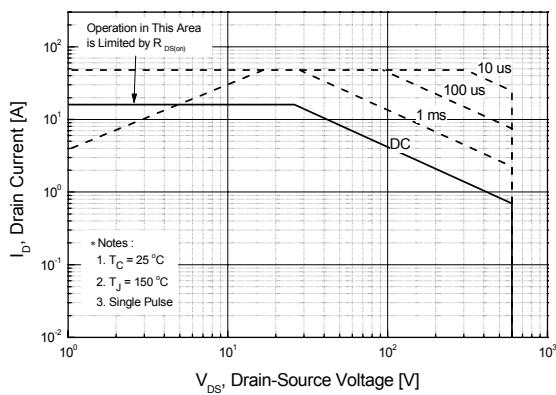
**Figure 7. Breakdown Voltage Variation vs. Temperature**



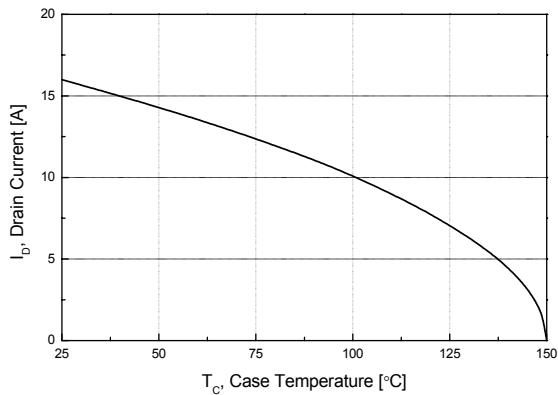
**Figure 8. On-Resistance Variation vs. Temperature**



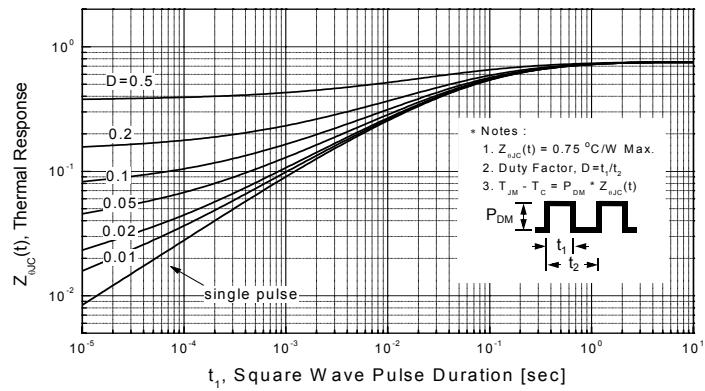
**Figure 9. Maximum Safe Operating Area**



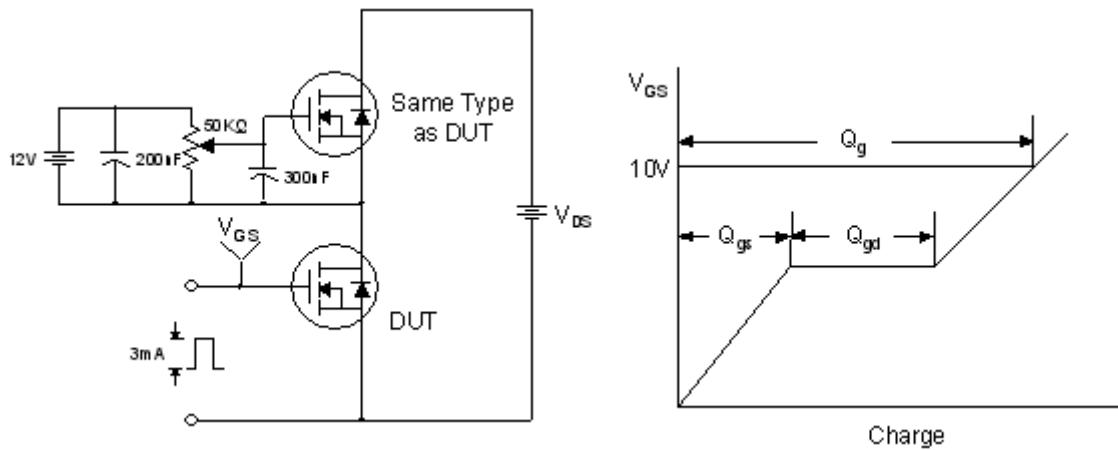
**Figure 10. Maximum Drain Current vs. Case Temperature**



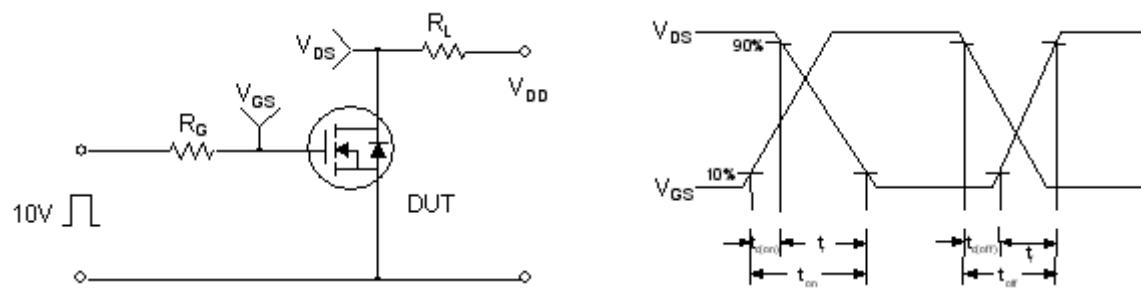
**Figure 11. Transient Thermal Response Curve**



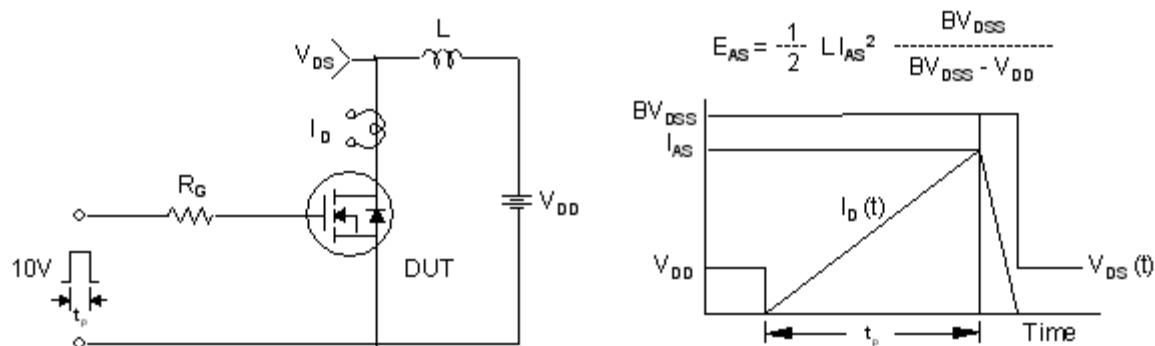
Gate Charge Test Circuit & Waveform



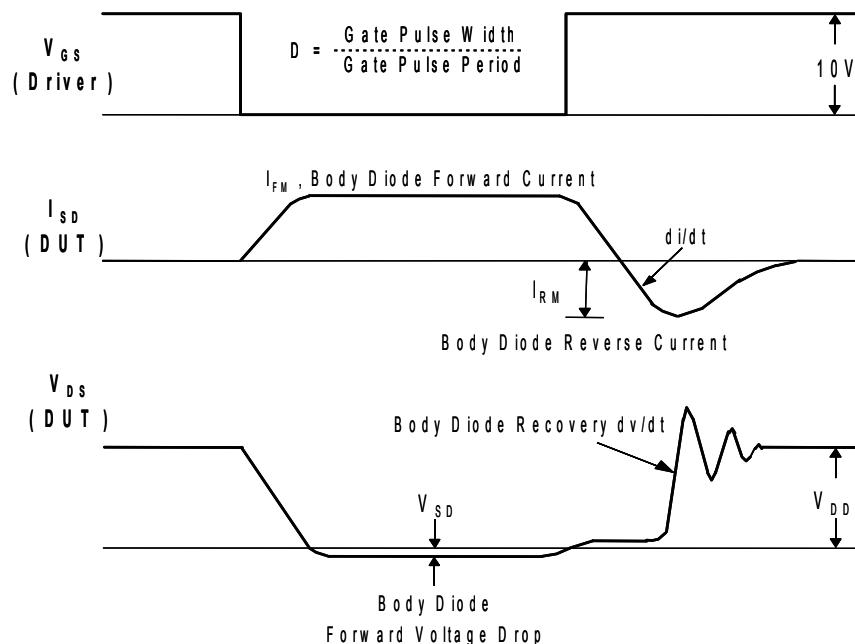
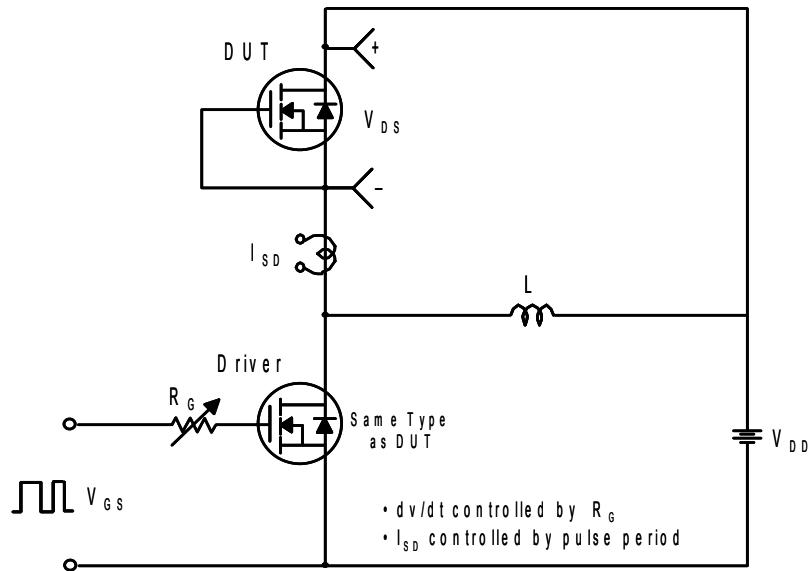
Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching Test Circuit & Waveforms

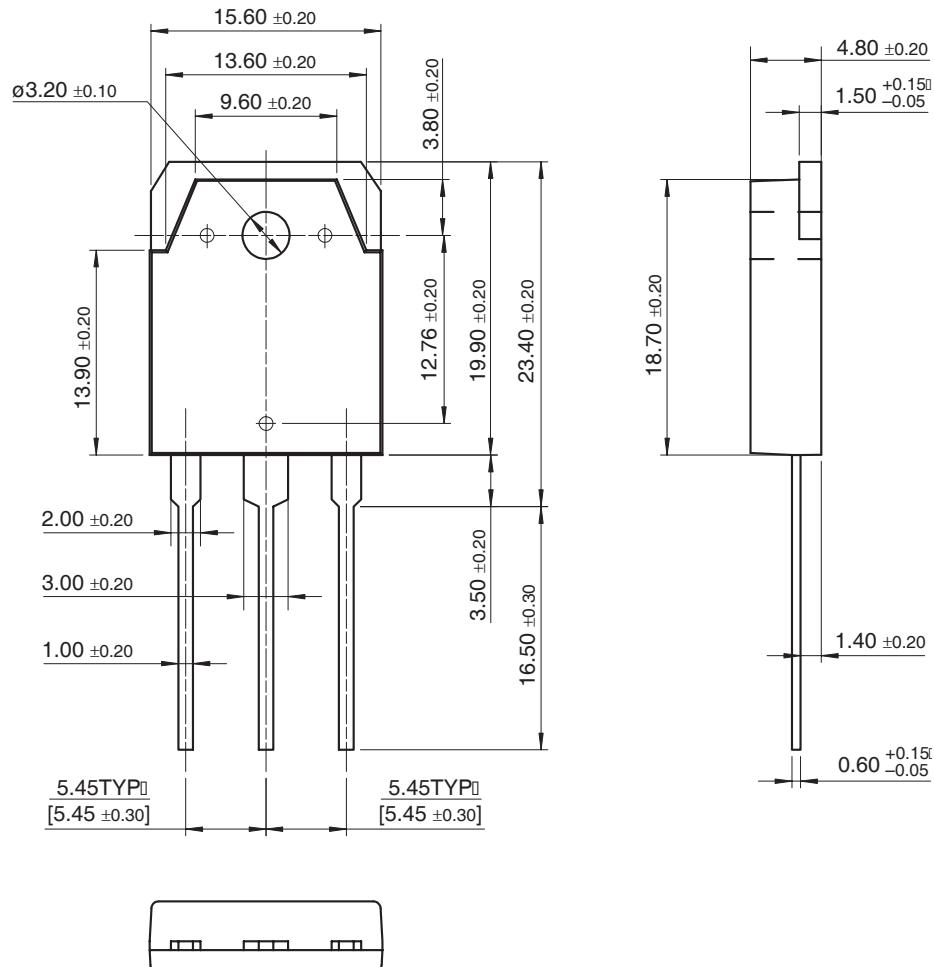


## Peak Diode Recovery dv/dt Test Circuit &amp; Waveforms

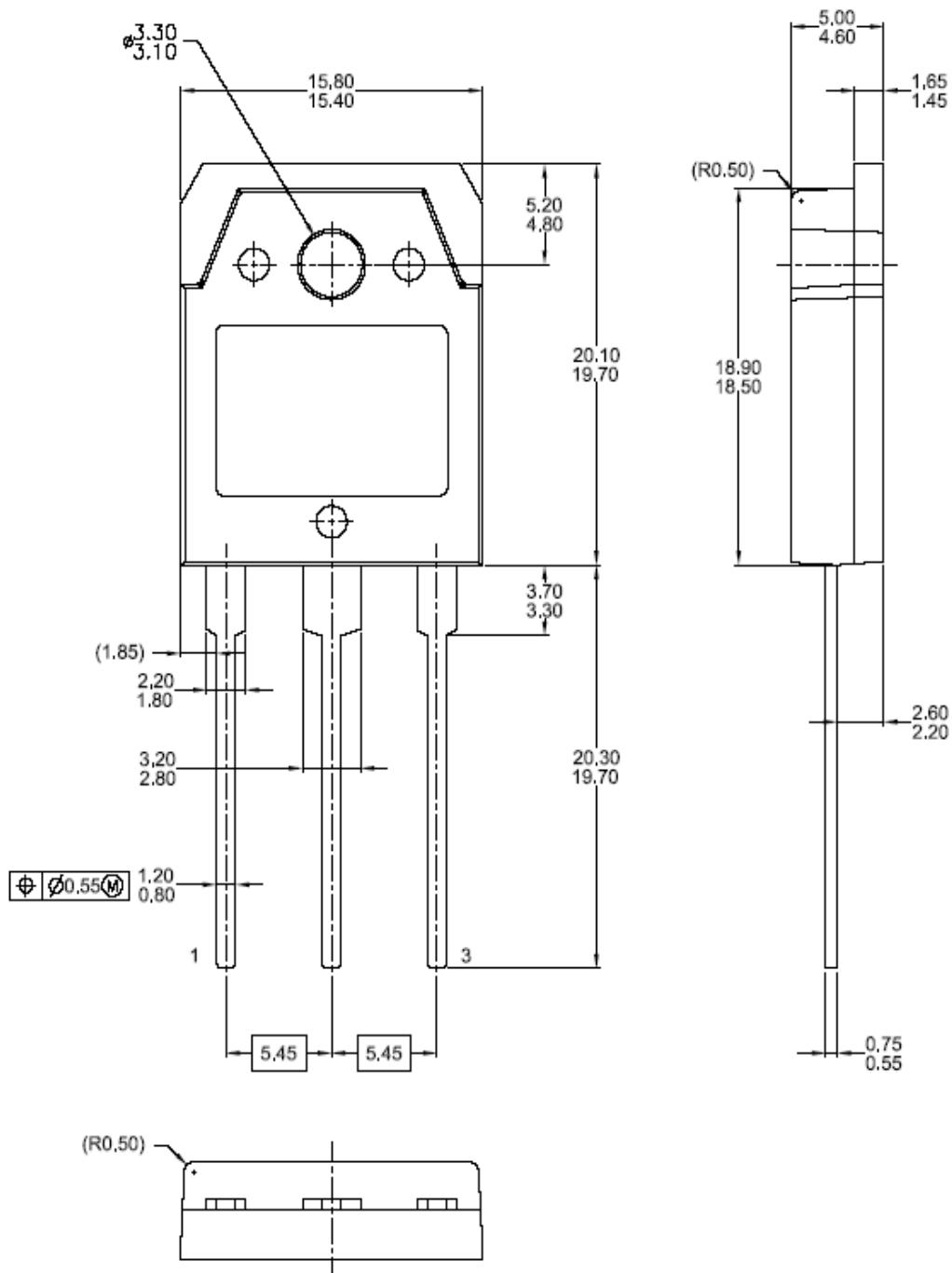


## Mechanical Dimensions

TO-3P



Dimensions in Millimeters

**Mechanical Dimensions (continued)****TO-3PN**

Dimensions in Millimeters

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No Identification Needed	Full Production	This datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
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